

APPROVAL SHEET

MULTILAYER CERAMIC CAPACITORS

Low Profile Series

0402 to 1210 Sizes

X7R, X5R & Y5V Dielectrics

RoHS Compliance

*Contents in this sheet are subject to change without prior notice.



1. DESCRIPTION

MLCC consists of a conducting material and electrodes. To manufacture a chip-type SMT and achieve miniaturization, high density and high efficiency, ceramic condensers are used.

WTC TT series MLCC is used in product having thickness concerned generally have high capacitance and thinner product thickness. The high dielectric constant material X7R, X5R and Y5V are used for this series product.

2. FEATURES

- a. Standard size with thin thickness.
- b. Small size with high capacitance.
- c. Capacitor with lead-free termination (pure Tin).

3. APPLICATIONS

- a. For LCD panels.
- b. For PCMCA cards.
- c. For IC packaging and modules.
- d. Any thickness concerned products.

4. HOW TO ORDER

<u> </u>	<u>31</u>	<u>X</u>	<u>225</u>	<u>K</u>	<u>100</u>	<u>C</u>	I
<u>Series</u>	<u>Size</u>	Dielectric	Capacitance	<u>Tolerance</u>	Rated voltage	<u>Termination</u>	Packaging style
TT=Low profile	15=0402 (1005) 18=0603 (1608) 21=0805 (2012) 31=1206 (3216) 32=1210 (3225)	X =X5R F =Y5V	Two significant digits followed by no. of zeros. And R is in place of decimal point.	K=±10% M=±20% Z=-20/+80%	Two significant digits followed by no. of zeros. And R is in place of decimal point.	C =Cu/Ni/Sn	T=7" reel (paper tape) P=7" reel (plastic tape)
			eg.: 225=22x10 ⁵ =2,200,000pF =2.2µF		6R3 =6.3 VDC 100 =10 VDC 160 =16 VDC 250 =25 VDC 500 =50 VDC		

5. EXTERNAL DIMENSIONS

Size Inch (mm)	L (mm)	W (mm)	T ma: (mm)/Syr		M _B (mm)	
0402 (1005)	1.00±0.05	0.5±0.05	0.33	L	0.25±0.10	
0603 (1608)	1.6+0.15/-0.10	0.8+0.15/-0.10	0.60	Н	0.40±0.15	
0805 (2012)	2.00±0.20	1.25±0.20	0.95	Т	0.50±0.20	
1206 (2216)	2 20 . 0 20	1 60 . 0 20	0.95	Т	0.60.0.20	
1206 (3216)	3.20±0.20	1.60±0.20	1.30	J	0.60±0.20	
1210 (3225)	3.20±0.30	2.50±0.20	0.95	Т	0.75±0.25	

Fig. 1 The outline of MLCC

^{*} Reflow soldering process only is recommended.



6. GENERAL ELECTRICAL DATA

Dielectric	X7R	X5R	Y5V		
Size	1206	0402, 0603, 0805	i, 1206, 1210		
Capacitance range*	1.0µF	0.22μF to 10μF	1.0μF to 10μF		
Capacitance tolerance**	K (±10%	Z (-20/+80%)			
Rated voltage (WVDC)	25V	6.3V, 10V, 16V, 25V	10V, 16V, 25V, 50V		
Tan δ*	25V: ≤10%	25V, 16V, 10V: ≤10%; 6.3V: ≤15.0%	50V: ≤7.0% 25V: ≤9.0% 16V, 10V: ≤12.5%		
Insulation resistance at Ur		RxC≥100ΩxF			
Operating temperature	-55 to +125℃	-55 to +85℃	-25 to +85℃		
Capacitance characteristic	±15% +30/-809				
Termination	Ni/Sn (lead-free termination)				

^{*} Measured at 1.0±0.2Vrms, 1.0kHz±10%, 30~70% related humidity, 25℃ ambient temperature for X7R, X5R and at 20℃ for Y5V.

7. CAPACITANCE RANGE

7-1 X7R & X5R dielectric

	Dielectric	X7R							X5	R							
	Size	1206	04	0402 0603			0805			1206				1210			
Rate	ed voltage (VDC)	25	6.3	25	10	16	6.3	10	16	25	6.3	10	16	25	50	10	25
	0.22uF (224)			L	Н	Н											
	0.47uF (474)			L													
a	1.0µF (105)	Т	L		Н	Н		Т	Т	Т		Т	Т	Т			
e e	1.5µF (155)							Т	Т			Т	Т	Т			
ital	2.2µF (225)						Т	Т	Т	Т		Т	Т	Т	Т		
ac	3.3µF (335)											Т	Т	Т		Т	
Capacitance	4.7µF (475)						Т	Т	Т			Т	Т	Т		Т	
	6.8µF (685)																
	10μF (106)						Т	Т			J	J/T		Т			Т
	22uF (226)						Т				Т						

7-2 Y5V dielectric

	Dielectric	Y5V									
	Size	0805				12	1210				
Rate	ed voltage (VDC)	10	16	25	50	10	16	25	50	10	16
	1.0µF (105)				T						
a)	1.5µF (155)										
Capacitance	2.2µF (225)		Т	Т		Т	Т	Т	Т		
Ē	3.3µF (335)	Т									
Sac	4.7μF (475)	Т	Т			Т	Т	Т			
Sa	6.8µF (685)					Т					
	10μF (106)	Т				Т				Т	
	22µF (226)										

8. PACKAGING STYLE AND QUANTITY

Size	Thickness May (m	m\/Symbol	7" reel			
Size	Thickness Max (mm)/Symbol		Paper tape	Plastic tape		
0402 (1005)	0.33	L	15k	-		
0603 (1608)	0.60	Н	4k	-		
0805 (2012)	0.95	Т	4k	-		
4000 (0040)	0.95	Т	4k	-		
1206 (3216)	1.30	J	-	3k		
1210 (3225)	0.95	Т	-	3k		

Unit: pieces

^{**} Preconditioning for Class II MLCC: Perform a heat treatment at 150±10℃ for 1 hour, then leave in a mbient condition for 24±2 hours before measurement.



9. RELIABILITY TEST CONDITIONS AND REQUIREMENTS

No.	Item		Test Condition					Requirements	
1.	Visual and				* N	No remarkat	ble def	ect.	
	Mechanical				* [Dimensions	to con	form to individual specific	ation sheet.
2.	Capacitance	Cap≤10µF, 1.	0±0.2Vrms, 1kHz±10%		* 5	Shall not exc	ceed th	ne limits given in the detai	iled spec.
3.	Q/ D.F.	Cap>10µF, 0.	5±0.2Vrms, 120Hz±20%**		X7R/X5R:				
	(Dissipation	** Test conditi	ion: 0.5±0.2Vrms , 1KHz±10%			Rated vol.		D.F.	
	Factor)	TT18X≧4	75(10V), TT15X series			25V, 16V, 1	0V	≤10%	
	-					6.3V		≤15%	
						Y5V:			
					1	Rated vol.		D.F.	
					8	50V		≤7%	
					ē 1	25V		≤9%	
4					H	16V/10V		≤12.5%	
4.	Dielectric		tage: 250% rated voltage.		* 1	No evidence	of dar	nage or flash over during	test.
	Strength	* Duration: 1 t							
_			discharge current less than 50m/						
_	Insulation	To apply rated	d voltage for max. 120 sec.		≥1	0GΩ or Rx0	C≥1009	Ω-F whichever is smaller.	
	Resistance								
6.	Temperature	With no electr	rical load.		_				_
	Coefficient	T.C.	Operating Temp		Т.	C.	Capac	itance Change	
		X7R	-55~125℃ at 25℃		:-	7R		±15%	4
		X5R	-55~85℃ at 25℃		-	5R	Within		
_		Y5V	-25~85℃ at 20℃		₽	5V	l .	+30%/-80%	
	Adhesive	•	g force : 5N (≤0603) and 10N (>0	603)	* 1	No remarkat	ble dan	nage or removal of the te	rminations.
	Strength of	* Test time: 10	0±1 sec.						
_	Termination				<u>L</u>				
8.	Vibration		equency: 10~55 Hz/min.		* No remarkable damage.				
	Resistance	* Total amplitu			* Cap change and Q/D.F.: To meet initial spec.				
			hrs. (Two hrs each in three mutua	ally					
		perpendicular	*						
			nt to be made after keeping at roo	om temp. for					
_	0.11	24±2 hrs.			0.5	.01			
9.	Solderability	i '	perature: 235±5℃		95	% min. cov	erage	of all metalized area.	
40	D		e: 2±0.5 sec.						
10.	Bending Test	E	part of substrate shall be pressure	-	3			nage.	
		1	rizing rod at a rate of about 1 mm						
			becomes 1 mm and then the pre	ssure shall be	8	(7R/X5R: w/ ′5V: within ±		12.5%	
		maintained fo			1			anna maana tha ahanaa	of conscitones under
			nt to be made after keeping at roo	om temp. for	≣ `	<u>=</u>		nange means the change	•
		24±2 hrs			specified flexure of substrate from the capacitance measured before				iance measureu beiore
11	Resistance to	* Colder tors	organico: 260±5°C		•	e test.)	blo dos	mago	
	Soldering Heat	•	perature: 260±5℃		* No remarkable damage.				
	Columning riedl			imme rse the	* Cap change:				
		* Preheating: 120 to 150°C for 1 minute before imme rse the capacitor in a eutectic solder.							
		≣ [']	l measurement (Class II only): Pe	erform	Y5V: within ±20%				
		<u> </u>	for 1 hr and then set for 24±2 hrs		* Q/D.F., I.R. and dielectric strength: To meet initial requirements. * 25% max. leaching on each edge.				
			nt to be made after keeping at roo	•	4	Lo /o max. le	aumi	g on each euge.	
		24±2 hrs.	at the second delivery						
		_ 1 1110.			<u>: </u>				

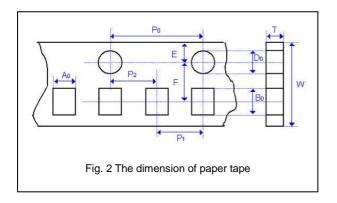


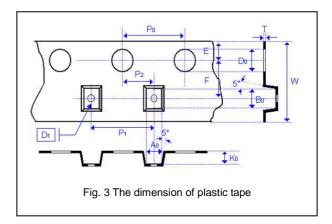
No.	Item			Test Condition	on	Req	uirements		
12.	Temperature	* Conduct	the five cyc	les according to t	he temperatures and	emarkable damage.			
	Cycle	time.				change:			
	-	Step		Temp. (℃)	Time (min.)	R/X5R: within ±7.5%			
		1		ing temp. +0/-3	30±3	Y5V: within ±20%			
		2	Room temp		2~3		ength: To meet initial requirements.		
		3		ting temp. +3/-0	30±3	.i ., i.rt. and dicicotile sti	erigin. To meet illiaar requirements.		
		4	Room temp		2~3				
		* Before i		rement (Class II o					
		1		•	4±2 hrs at room temp.				
		1			ng at room temp. for				
			ement to be	illade alter keepii	ig at room temp. for				
40		24±2 hrs.				emarkable damage.			
	Humidity	* Test tem	ıp.: 40±2℃			change: X7R/X5R: wit	hin ±25%		
	(Damp Heat)	* Humidity	/: 90~95% R	RH			30%; 6.3V, within +30/-40%		
	Steady State	* Test time	e: 500+24/-0	hrs.		F. value:			
		*Before in	itial measur	ement (Class II o	nly): Perform	R/X5R:			
		150+0/-10	℃ for 1 hr a	and then set for 24	4±2 hrs at room temp.	ted vol. D.F.			
		* Measure	ement to be	made after keepii	ng at room temp. for	/, 16V ≤15%			
		24±2 hrs.				/ ≤20%			
		Z IZZ IIIO.				V ≤30%			
						,			
						/: 			
						ted vol. D.F.			
						/ ≤10%			
						/ ≤15%			
						/, 10V ≤20%			
						1GΩ or RxC≧10 Ω-F which	chever is smaller.		
14.	Humidity	* Test tem	p.: 40±2℃			emarkable damage.	-in .250/		
	(Damp Heat)	* Humidity: 90~95%RH				change: X7R/X5R: with Y5V: within ±3	30%; 6.3V, within +30/-40%		
	Load	* Test time: 500+24/-0 hrs.							
	Loud	1				F. value:			
			-	ated voltage.		R/X5R:			
		•		· ·	only): To apply test	ted vol. D.F.			
		voltage fo	r 1hr at 40℃	and then set for	24±2 hrs at room temp	/, 16V ≤15%			
		* Measure	ement to be	made after keepii	ng at room temp. for	/ ≤20%			
		24±2 hrs				V ≤30%			
						<u>/:</u>			
						ed vol. D.F.			
						/ ≤10%			
						/ ≤15%			
						/, 10V ≤20%			
						500MΩ or RxC \ge 5 Ω-F v	vhichever is smaller.		
15.	High	* Test tem	р. :			emarkable damage.			
	Temperature	NP0, X7	R/X7E: 125:	±3℃		change: X7R/X5R: with			
	Load	X5R, Y5	V: 85±3℃				30%; 6.3V, within +30/-40%		
		-	: 1000+24/-			F. value:			
	(Endurance)			6 of rated voltage.		/X5R:			
				ge for below range	Capacitance	ted vol. D.F.			
		Size	Dielectric	Rated voltage	range	/, 16V ≤15%			
		TT18	Y5V	6.3V,10V	C≧2.2µF	/ ≤20%			
		TT21	Y5V	6.3V	C≧10µF	V ≤30%			
		TT31	Y5V	6.3V	C≧22μF				
		1131	134	0.57	O≘∠∠μι	:			
		*Dofo	itial ma	omont (Class II	alvi. To cook to	ted vol. D.F.			
		1		•	nly): To apply test	/ ≤10%			
	voltage for 1hr at test temp. and then set for 24±2 hrs at room temp.					/ ≤10% / ≤15%			
		*Measure	ment to be r	nade after keepin	g at room temp. for	/, 10V ≤20%			
		24±2 hrs		-	•				
		1				1GΩ or RxC≧10 Ω-F which	hever is smaller.		
		•							



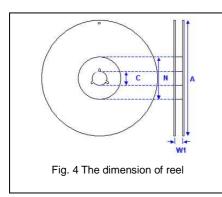
APPENDIXES

■ Tape & reel dimensions





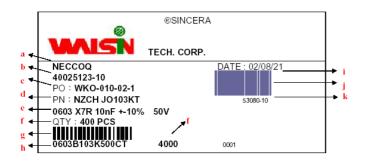
Size	0402	0603	0805	12	206	1210
Thickness	L	Н	Т	Т	J	T
A ₀	0.62±0.05	1.10±0.10	1.50±0.10	2.00±0.10	<1.85	<2.97
B ₀	1.12±0.05	1.90±0.10	2.30±0.10	3.50±0.10	<3.46	<3.73
Т	0.42±0.05	0.60±0.05	0.95±0.05	0.95±0.05	0.23±0.05	0.23±0.05
K ₀	-		-	-	<2.50	<2.50
w	8.00±0.10	8.00±0.10	8.00±0.10	8.00±0.10	8.00±0.10	8.00±0.10
P ₀	4.00±0.10	4.00±0.10	4.00±0.10	4.00±0.10	4.00±0.10	4.00±0.100
10xP ₀	40.0±0.10	40.0±0.10	40.0±0.10	40.0±0.10	40.0±0.10	40.0±0.10
P ₁	2.00±0.05	2.00±0.05	4.00±0.10	4.00±0.10	4.00±0.10	4.00±0.10
P ₂	2.00±0.05	2.00±0.05	2.00±0.05	2.00±0.05	2.00±0.05	2.00±0.05
D_0	1.55±0.05	1.55±0.05	1.55±0.05	1.50±0.05	1.50±0.05	1.50±0.05
D ₁	-		-	-	1.00±0.10	1.00±0.10
E	1.75±0.05	1.75±0.05	1.75±0.05	1.75±0.10	1.75±0.10	1.75±0.10
F	3.50±0.05	3.50±0.05	3.50±0.05	3.50±0.05	3.50±0.05	3.50±0.05



Size	040	0402, 0603, 0805, 1206, 1210						
Reel size	7"	10"	13"					
С	13.0+0.5/-0.2	13.0+0.5/-0.2	13.0+0.5/-0.2					
\mathbf{W}_1	8.4+1.5/-0	8.4+1.5/-0	8.4+1.5/-0					
Α	178.0±0.10	250.0±1.0	330.0±1.0					
N	60.0+1.0/-0	100.0±1.0	100±1.0					



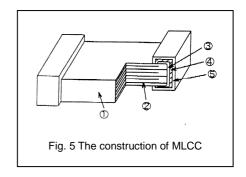
Description of customer label



- a. Customer name
- b. WTC order series and item number
- c. Customer P/O
- d. Customer P/N
- e. Description of product
- f. Quantity
- g. Bar code including quantity & WTC P/N or customer
- h. WTC P/N
- i. Shipping date
- j. Order bar code including series and item numbers
- k. Serial number of label

Constructions

No.	Nam	ne	X7R, X5R, Y5V
1	Ceramic r	naterial	BaTiO₃ based
2	Inner ele	ctrode	Ni
3		Inner layer	Cu
4	Termination	Middle layer	Ni
(5)		Outer layer	Sn (Matt)



Storage and handling conditions

- (1) To store products at 5 to 40°C ambient temperature and 20 to 70%. related humidity conditions.
- (2) The product is recommended to be used within one year after shipment. Check solderability in case of shelf life extension is needed.

Cautions:

- a. The corrosive gas reacts on the terminal electrodes of capacitors, and results in the poor solderability. Do not store the capacitors in the ambience of corrosive gas (e.g., hydrogen sulfide, sulfur dioxide, chlorine, ammonia gas etc.)
- b. In corrosive atmosphere, solderability might be degraded, and silver migration might occur to cause low reliability.
- c. Due to the dewing by rapid humidity change, or the photochemical change of the terminal electrode by direct sunlight, the solderability and electrical performance may deteriorate. Do not store capacitors under direct sunlight or dewing condition. To store products on the shelf and avoid exposure to moisture.



■ Recommended soldering conditions

The lead-free termination MLCCs are not only to be used on SMT against lead-free solder paste, but also suitable against lead-containing solder paste. If the optimized solder joint is requested, increasing soldering time, temperature and concentration of N_2 within oven are recommended.

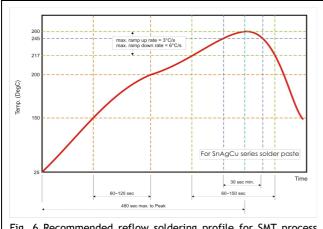


Fig. 6 Recommended reflow soldering profile for SMT process with ${\sf SnAgCu}$ series solder paste.

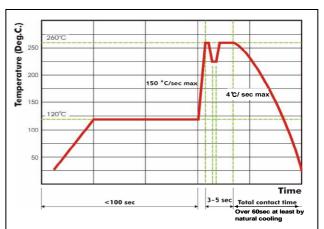


Fig. 7 Recommended wave soldering profile for SMT process with ${\sf SnAgCu}$ series solder.